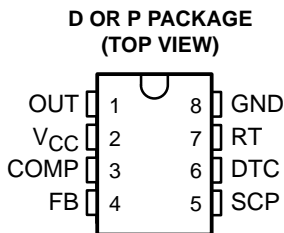


# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

SLVS084C – APRIL 1994 – REVISED SEPTEMBER 1995

- Complete PWM Power Control
- 3.6-V to 40-V Operation
- Internal Undervoltage-Lockout Circuit
- Internal Short-Circuit Protection
- Oscillator Frequency . . . 40 kHz to 400 kHz
- Variable Dead Time Provides Control Over Total Range



## description

The TL5001 incorporates on a single monolithic chip all the functions required for a pulse-width-modulation (PWM) control circuit. Designed primarily for power-supply control, the TL5001 contains an error amplifier, a regulator, an oscillator, a PWM comparator with a dead-time-control input, undervoltage lockout (UVLO), short-circuit protection (SCP), and an open-collector output transistor.

The error-amplifier common-mode voltage ranges from 0 V to 1.5 V. The noninverting input of the error amplifier is connected to a 1-V reference. Dead-time control (DTC) can be set to provide 0% to 100% dead time by connecting an external resistor between DTC and GND. The oscillator frequency is set by terminating RT with an external resistor to GND. During low  $V_{CC}$  conditions, the UVLO circuit turns the output off until  $V_{CC}$  recovers to its normal operating range.

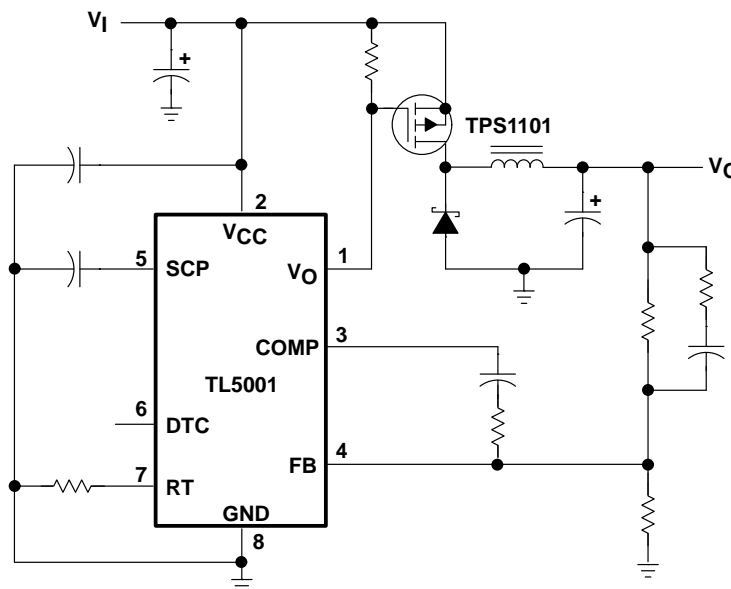
The TL5001C is characterized for operation from  $-20^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ . The TL5001I is characterized for operation from  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$ .

## AVAILABLE OPTIONS

$T_A$	PACKAGED DEVICES		
	SMALL OUTLINE (D)	PLASTIC DIP (P)	CHIP FORM (Y)
$-20^{\circ}\text{C}$ to $85^{\circ}\text{C}$	TL5001CD	TL5001CP	TL5001Y
$-40^{\circ}\text{C}$ to $85^{\circ}\text{C}$	TL5001ID	TL5001IP	—

The D package is available taped and reeled. Add the suffix R to the device type (e.g., TL5001CDR). Chip forms are tested at  $T_A = 25^{\circ}\text{C}$ .

## schematic for typical application



PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



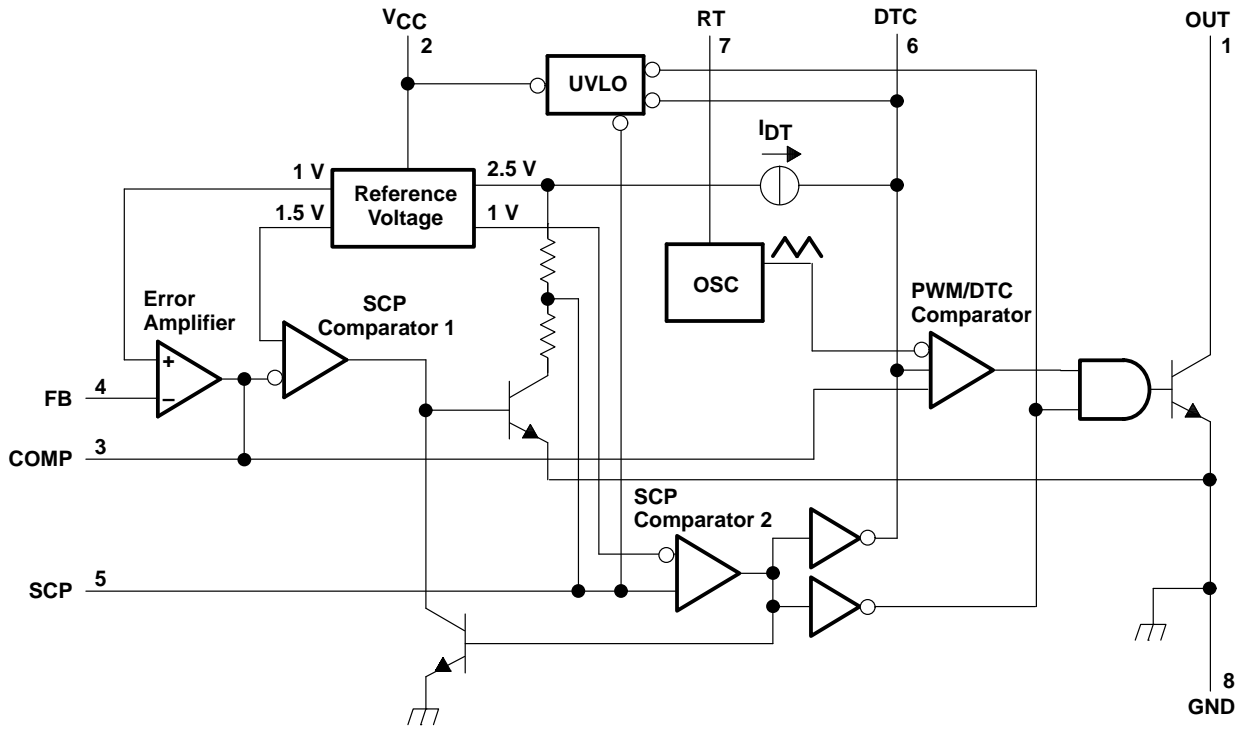
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# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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## functional block diagram

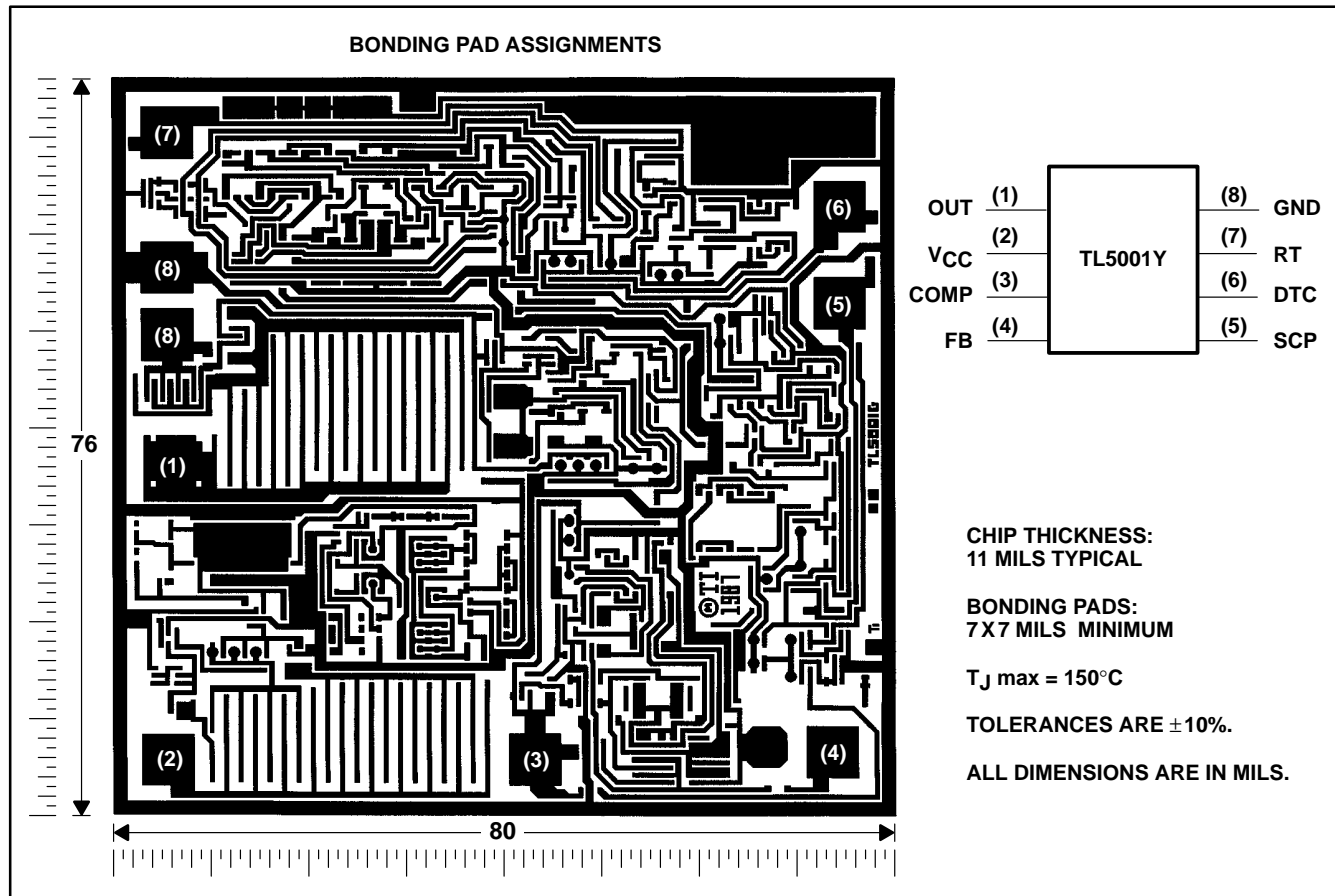


# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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## TL5001Y chip information

This chip, when properly assembled, displays characteristics similar to the TL5001C. Thermal compression or ultrasonic bonding may be used on the doped aluminum bonding pads. The chips may be mounted with conductive epoxy or a gold-silicon preform.



# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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### detailed description

#### voltage reference

A 2.5-V regulator operating from  $V_{CC}$  is used to power the internal circuitry of the TL5001 and as a reference for the error amplifier and SCP circuits. A resistive divider provides a 1-V reference for the error amplifier noninverting input. The 1-V reference remains within 5% of nominal over the operating temperature range.

#### error amplifier

The error amplifier compares a sample of the dc-to-dc converter output voltage to the 1-V reference and generates an error signal for the PWM comparator. The dc-to-dc converter output voltage is set by selecting the error-amplifier gain (see Figure 1), using the following expression:

$$V_O = (1 + R1/R2) (1 \text{ V})$$

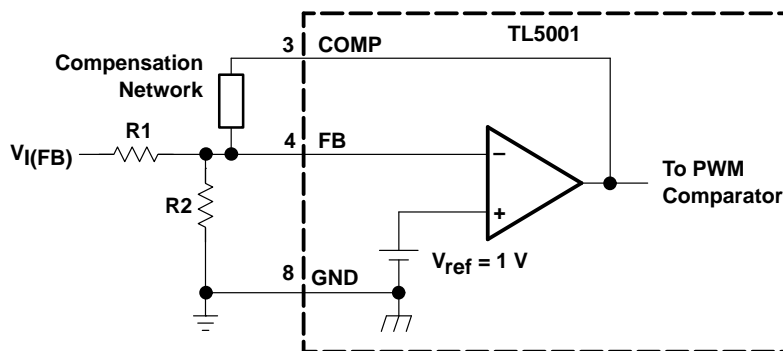


Figure 1. Error-Amplifier Gain Setting

#### error amplifier (continued)

The error-amplifier output is brought out as COMP for use in compensating the dc-to-dc converter control loop for stability. Because the amplifier can only source 45  $\mu\text{A}$ , the total dc load resistance should be 100 k $\Omega$  or more.

#### oscillator/PWM

The oscillator frequency ( $f_{osc}$ ) can be set between 40 kHz and 400 kHz by connecting a resistor between RT and GND. Acceptable resistor values range from 15 k $\Omega$  to 250 k $\Omega$ . The oscillator frequency can be determined by using the graph shown in Figure 5.

The oscillator output is a triangular wave with a minimum value of approximately 0.7 V and a maximum value of approximately 1.3 V. The PWM comparator compares the error-amplifier output voltage and the DTC input voltage to the triangular wave and turns the output transistor off whenever the triangular wave is greater than the lesser of the two inputs.

#### dead-time control (DTC)

DTC provides a means of limiting the output-switch duty cycle to a value less than 100%, which is critical for boost and flyback converters. A current source generates a reference current ( $I_{DT}$ ) at DTC that is nominally equal to the current at the oscillator timing terminal, RT. Connecting a resistor between DTC and GND generates a dead-time reference voltage ( $V_{DT}$ ), which the PWM/DTC comparator compares to the oscillator triangle wave as described in the previous section. Nominally, the maximum duty cycle is 0% when  $V_{DT}$  is 0.7 V or less and 100% when  $V_{DT}$  is 1.3 V or greater. Because the triangle wave amplitude is a function of frequency and the source impedance of RT is relatively high (1250  $\Omega$ ), choosing  $R_{DT}$  for a specific maximum duty cycle, D, is accomplished using the following equation and the voltage limits for the frequency in question as found in Figure 11 ( $V_{osc,max}$  and  $V_{osc,min}$  are the maximum and minimum oscillator levels):

$$R_{DT} = (R_t + 1250) [D(V_{oscmax} - V_{oscmin}) + V_{oscmin}]$$

where

$R_{DT}$  and  $R_t$  are in ohms,  $D$  in decimal

Soft start can be implemented by paralleling the DTC resistor with a capacitor ( $C_{DT}$ ) as shown in Figure 2. During soft start, the voltage at DTC is derived by the following equation:

$$V_{DT} \approx I_{DT}R_{DT} \left( 1 - e^{-t/R_{DT}C_{DT}} \right)$$

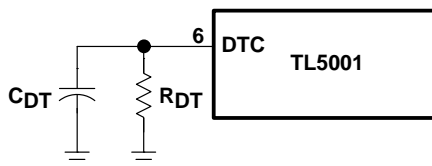


Figure 2. Soft-Start Circuit

If the dc-to-dc converter must be in regulation within a specified period of time, the time constant,  $R_{DT}C_{DT}$ , should be  $t_0/3$  to  $t_0/5$ . The TL5001 remains off until  $V_{DT} \approx 0.7$  V, the minimum ramp value.  $C_{DT}$  is discharged every time UVLO or SCP becomes active.

#### undervoltage-lockout (UVLO) protection

The undervoltage-lockout circuit turns the output transistor off and resets the SCP latch whenever the supply voltage drops too low (approximately 3 V) for proper operation. A hysteresis voltage of 200 mV eliminates false triggering on noise and chattering.

#### short-circuit protection (SCP)

The TL5001 includes short-circuit protection (see Figure 3), which turns the power switch off to prevent damage when the converter output is shorted. When activated, the SCP prevents the switch from being turned on until the internal latching circuit is reset. The circuit is reset by reducing the input voltage until UVLO becomes active or until the SCP terminal is pulled to ground externally.

When a short circuit occurs, the error-amplifier output at COMP rises to increase the power-switch duty cycle in an attempt to maintain the output voltage. SCP comparator 1 starts an RC timing circuit when COMP exceeds 1.5 V. If the short is removed and the error-amplifier output drops below 1.5 V before time out, normal converter operation continues. If the fault is still present at the end of the time-out period, the timer sets the latching circuit and turns off the TL5001 output transistor.

# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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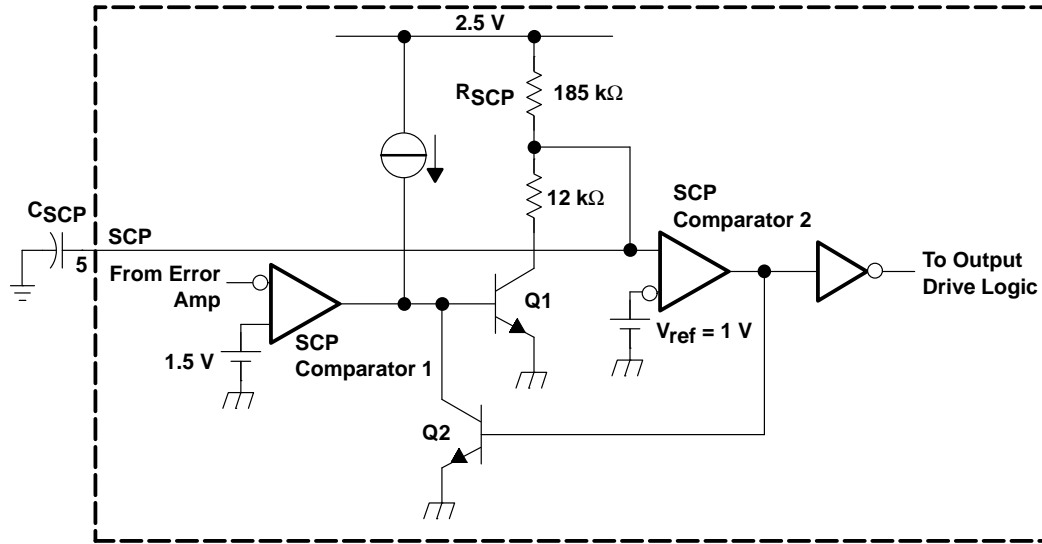


Figure 3. SCP Circuit

The timer operates by charging an external capacitor ( $C_{SCP}$ ), connected between the SCP terminal and ground, towards 2.5 V through a 185-k $\Omega$  resistor ( $R_{SCP}$ ). The circuit begins charging from an initial voltage of approximately 185 mV and times out when the capacitor voltage reaches 1 V. The output of SCP comparator 2 then goes high, turns on Q2, and latches the timer circuit. The expression for setting the SCP time period is derived from the following equation:

$$V_{SCP} = (2.5 - 0.185)\left(1 - e^{-t/\tau}\right) + 0.185$$

where

$$\tau = R_{SCP}C_{SCP}$$

The end of the time-out period,  $t_{SCP}$ , occurs when  $V_{SCP} = 1$  V. Solving for  $C_{SCP}$  yields:

$$C_{SCP} = 12.46 \times t_{SCP}$$

where

$t$  is in seconds,  $C$  in  $\mu$ F.

$t_{SCP}$  must be much longer (generally 10 to 15 times) than the converter start-up period or the converter will not start.

## output transistor

The output of the TL5001 is an open-collector transistor with a maximum collector current rating of 21 mA and a voltage rating of 51 V. The output is turned on under the following conditions: the oscillator triangle wave is lower than both the DTC voltage and the error-amplifier output voltage, the UVLO circuit is inactive, and the short-circuit protection circuit is inactive.

# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, $V_{CC}$ (see Note 1)	41 V
Amplifier input voltage, $V_{I(FB)}$	20 V
Output voltage, $V_O$ , OUT	51 V
Output current, $I_O$ , OUT	21 mA
Output peak current, $I_{O(peak)}$ , OUT	100 mA
Continuous total power dissipation	See Dissipation Rating Table
Operating ambient temperature range, $T_A$ : TL5001C	–20°C to 85°C
TL5001I	–40°C to 85°C
Storage temperature range, $T_{stg}$	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to network ground terminal.

**DISSIPATION RATING TABLE**

PACKAGE	$T_A \leq 25^\circ\text{C}$	DERATING FACTOR	$T_A = 70^\circ\text{C}$	$T_A = 85^\circ\text{C}$
	POWER RATING	ABOVE $T_A = 25^\circ\text{C}$	POWER RATING	POWER RATING
D	725 mW	5.8 mW/°C	464 mW	377 mW
P	1000 mW	8.0 mW/°C	640 mW	520 mW

### recommended operating conditions

	MIN	MAX	UNIT	
Supply voltage, $V_{CC}$	3.6	40	V	
Amplifier input voltage, $V_{I(FB)}$	0	1.5	V	
Output voltage, $V_O$ , OUT		50	V	
Output current, $I_O$ , OUT		20	mA	
COMP source current		45	μA	
COMP dc load resistance	100		kΩ	
Oscillator timing resistor, $R_t$	15	250	kΩ	
Oscillator frequency, $f_{osc}$	40	400	kHz	
Operating ambient temperature, $T_A$	TL5001C	–20	85	°C
	TL5001I	–40	85	

# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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**electrical characteristics over recommended operating free-air temperature range,  $V_{CC} = 6\text{ V}$ ,  $f_{osc} = 100\text{ kHz}$  (unless otherwise noted)**

### reference

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Output voltage	COMP connected to FB	0.95	1	1.05	V
Input regulation	$V_{CC} = 3.6\text{ V to }40\text{ V}$		2	12.5	mV
Output voltage change with temperature	$T_A = -20^\circ\text{C to }25^\circ\text{C}$ (TL5001C)	-10	-1	10	mV/V
	$T_A = -40^\circ\text{C to }25^\circ\text{C}$ (TL5001I)	-10	-1	10	
	$T_A = 25^\circ\text{C to }85^\circ\text{C}$	-10	-2	10	

† All typical values are at  $T_A = 25^\circ\text{C}$ .

### undervoltage lockout

PARAMETER	TL5001C, TL5001I			UNIT
	MIN	TYP†	MAX	
Upper threshold voltage		3		V
Lower threshold voltage		2.8		V
Hysteresis	100	200		mV

† All typical values are at  $T_A = 25^\circ\text{C}$ .

### short-circuit protection

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
SCP threshold voltage	$T_A = 25^\circ\text{C}$	0.95	1.00	1.05	V
SCP voltage, latched	No pullup	140	185	230	mV
SCP voltage, UVLO standby	No pullup		60	120	mV
Timing resistance			185		k $\Omega$
SCP comparator 1 threshold voltage			1.5		V

† All typical values are at  $T_A = 25^\circ\text{C}$ .

### oscillator

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Frequency	$R_f = 100\text{ k}\Omega$		97		kHz
Standard deviation of frequency			15		kHz
Frequency change with voltage	$V_{CC} = 3.6\text{ V to }40\text{ V}$		1		kHz
Frequency change with temperature	$T_A = -20^\circ\text{C to }25^\circ\text{C}$	-4	-0.4	4	kHz
	$T_A = 25^\circ\text{C to }85^\circ\text{C}$	-4	-0.2	4	
Voltage at RT			1		V

† All typical values are at  $T_A = 25^\circ\text{C}$ .



# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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**electrical characteristics over recommended operating free-air temperature range,  $V_{CC} = 6\text{ V}$ ,  $f_{osc} = 100\text{ kHz}$  (unless otherwise noted) (continued)**

### dead-time control

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Output (source) current		$0.9 \times I_{RT}^{\ddagger}$		$1.1 \times I_{RT}$	$\mu\text{A}$
Input threshold voltage	Duty cycle = 0%	0.5	0.7		V
	Duty cycle = 100%		1.3	1.5	

† All typical values are at  $T_A = 25^\circ\text{C}$ .

‡ Output source current at RT

### error amplifier

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Input voltage	$V_{CC} = 3.6\text{ V to }40\text{ V}$	0		1.5	V
Input bias current		-160		-500	nA
Output voltage swing	Positive	1.5	2.3		V
	Negative		0.3	0.4	V
Open-loop voltage amplification			80		dB
Unity-gain bandwidth			1.5		MHz
Output (sink) current	$V_{I(FB)} = 1.2\text{ V}$ , COMP = 1 V	100	600		$\mu\text{A}$
Output (source) current	$V_{I(FB)} = 0.8\text{ V}$ , COMP = 1 V	-45	-90		$\mu\text{A}$

† All typical values are at  $T_A = 25^\circ\text{C}$ .

### output

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Output saturation voltage	$I_O = 10\text{ mA}$		1.5	2	V
Off-state current	$V_O = 50\text{ V}$ , $V_{CC} = 0$			10	$\mu\text{A}$
	$V_O = 50\text{ V}$			10	
Short-circuit output current	$V_O = 6\text{ V}$		40		mA

† All typical values are at  $T_A = 25^\circ\text{C}$ .

### total device

PARAMETER	TEST CONDITIONS	TL5001C, TL5001I			UNIT
		MIN	TYP†	MAX	
Standby supply current	Off state		1	1.5	mA
Average supply current	$R_f = 100\text{ k}\Omega$		1.1	2.1	mA

† All typical values are at  $T_A = 25^\circ\text{C}$ .

# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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electrical characteristics,  $V_{CC} = 6\text{ V}$ ,  $f_{osc} = 100\text{ kHz}$ ,  $T_A = 25^\circ\text{C}$  (unless otherwise noted)

### reference

PARAMETER	TEST CONDITIONS	TL5001Y			UNIT
		MIN	TYP	MAX	
Output voltage	COMP connected to FB		1		V
Input regulation	$V_{CC} = 3.6\text{ V to }40\text{ V}$		2		mV
Output voltage change with temperature			-2		mV/V

### undervoltage lockout

PARAMETER	TL5001Y			UNIT
	MIN	TYP	MAX	
Upper threshold voltage		3		V
Lower threshold voltage		2.8		V
Hysteresis		200		mV

### short-circuit protection

PARAMETER	TEST CONDITIONS	TL5001Y			UNIT
		MIN	TYP	MAX	
SCP threshold voltage			1		V
SCP voltage, latched	No pullup		185		mV
SCP voltage, UVLO standby	No pullup		60		mV
Timing resistance			185		k $\Omega$
SCP comparator 1 threshold voltage			1.5		V

### oscillator

PARAMETER	TEST CONDITIONS	TL5001Y			UNIT
		MIN	TYP	MAX	
Frequency	$R_t = 100\text{ k}\Omega$		97		kHz
Standard deviation of frequency			15		kHz
Frequency change with voltage	$V_{CC} = 3.6\text{ V to }40\text{ V}$		1		kHz
Frequency change with temperature			-0.4		kHz
			-0.2		
Voltage at RT			1		V

# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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**electrical characteristics,  $V_{CC} = 6\text{ V}$ ,  $f_{osc} = 100\text{ kHz}$ ,  $T_A = 25^\circ\text{C}$  (unless otherwise noted) (continued)**

### dead-time control

PARAMETER	TEST CONDITIONS	TL5001Y			UNIT
		MIN	TYP	MAX	
Input threshold voltage	Duty cycle = 0%	0.7			V
	Duty cycle = 100%	1.3			

### error amplifier

PARAMETER		TEST CONDITIONS	TL5001Y			UNIT
			MIN	TYP	MAX	
Input bias current			-160			nA
Output voltage swing	Positive		2.3			V
	Negative		0.3			V
Open-loop voltage amplification			80			dB
Unity-gain bandwidth			1.5			MHz
Output (sink) current		$V_{I(FB)} = 1.2\text{ V}$ , COMP = 1 V	600			$\mu\text{A}$
Output (source) current		$V_{I(FB)} = 0.8\text{ V}$ , COMP = 1 V	-90			$\mu\text{A}$

### output

PARAMETER	TEST CONDITIONS	TL5001Y			UNIT	
		MIN	TYP	MAX		
Output saturation voltage	$I_O = 10\text{ mA}$	1.5			2	V
Short-circuit output current	$V_O = 6\text{ V}$	40				mA

### total device

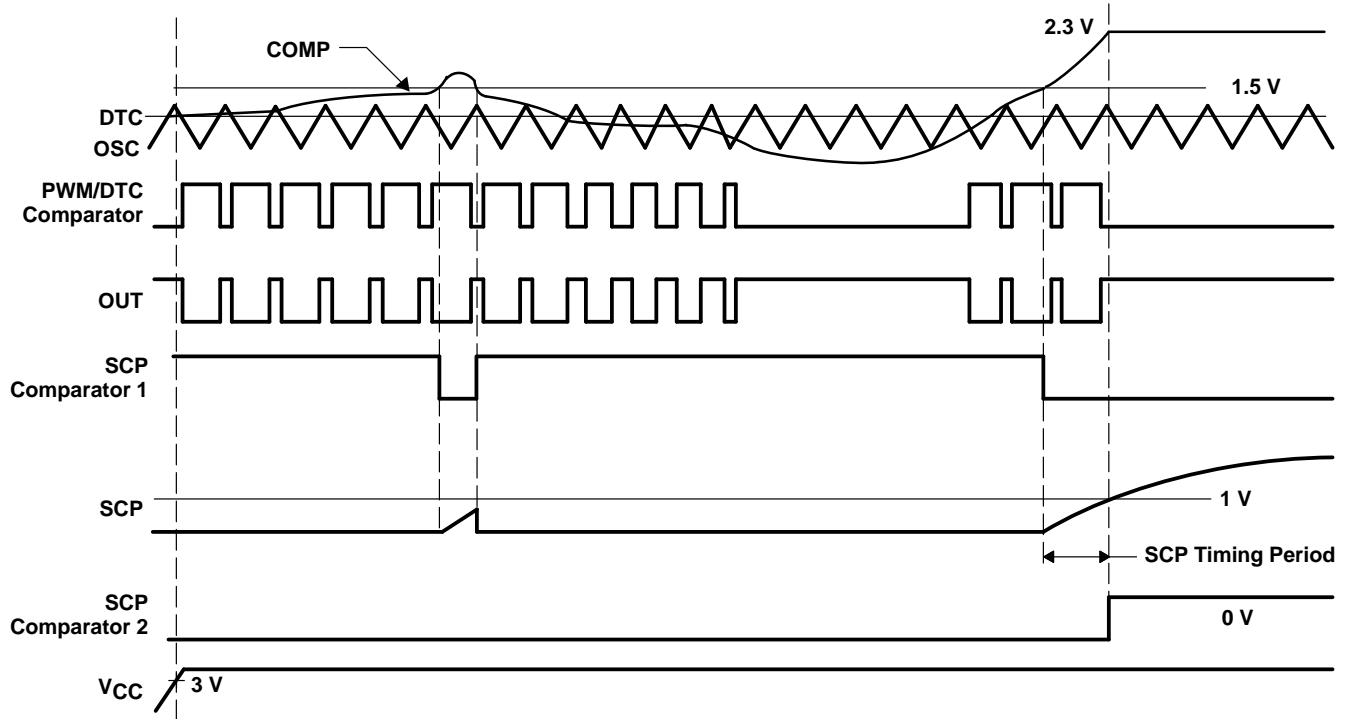
PARAMETER		TEST CONDITIONS	TL5001Y			UNIT
			MIN	TYP	MAX	
Standby supply current	Off state		1			mA
Average supply current		$R_t = 100\text{ k}\Omega$	1.1			mA



# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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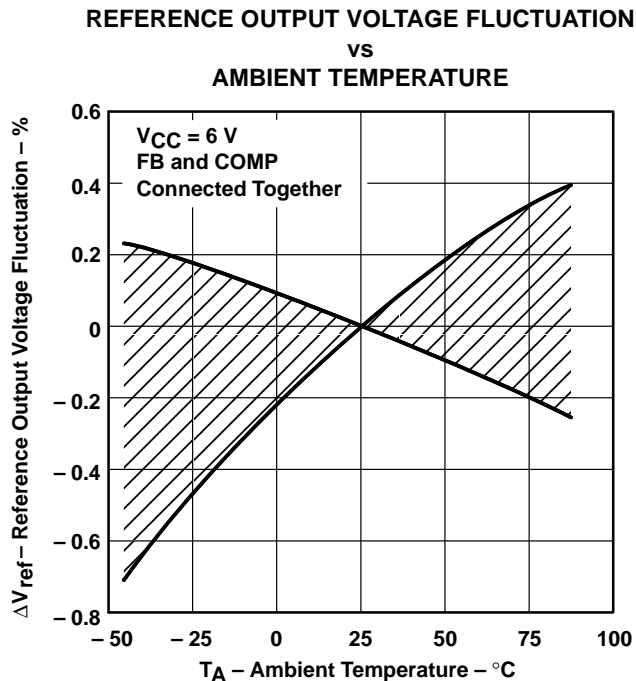
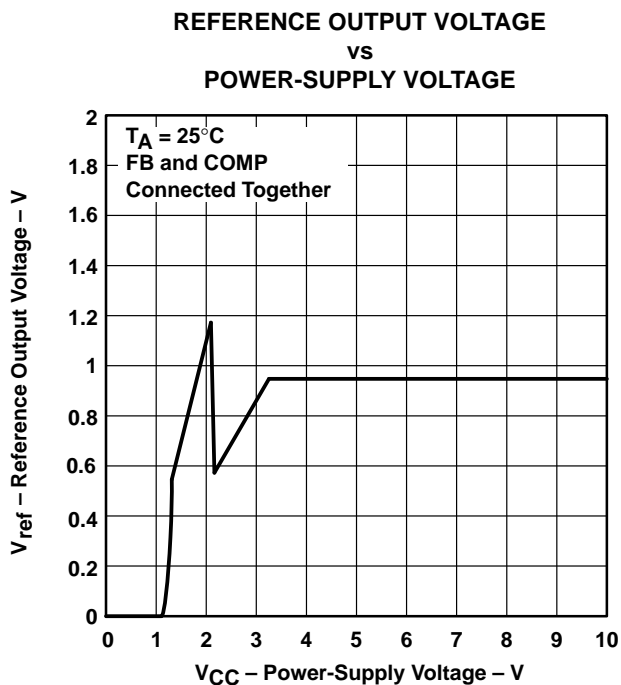
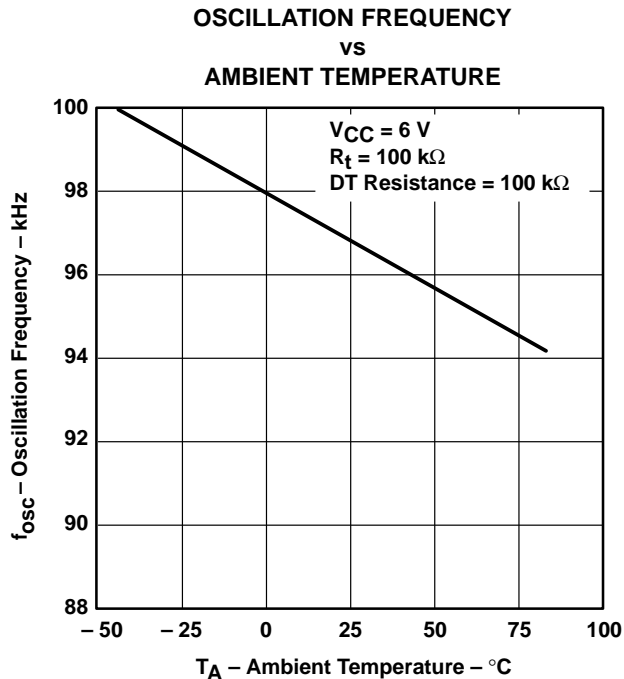
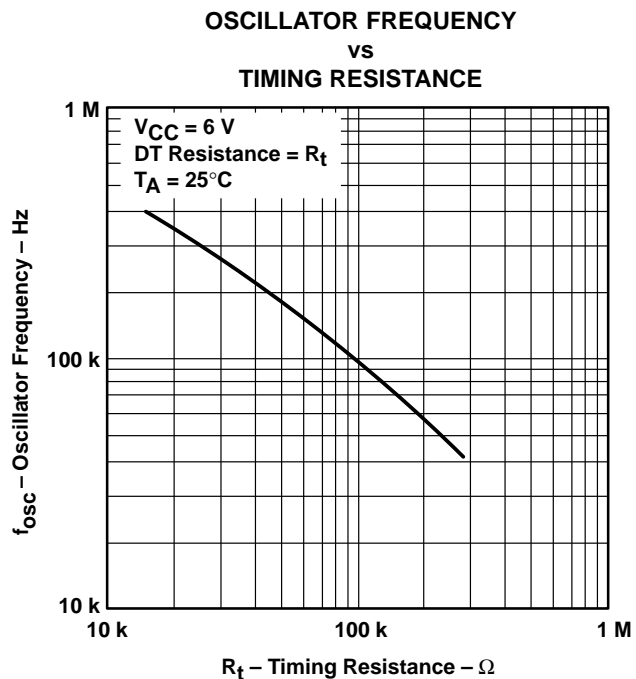
## PARAMETER MEASUREMENT INFORMATION



NOTE A. The waveforms show timing characteristics for an intermittent short circuit and a longer short circuit that is sufficient to activate SCP.

**Figure 4. PWM Timing Diagram**

TYPICAL CHARACTERISTICS

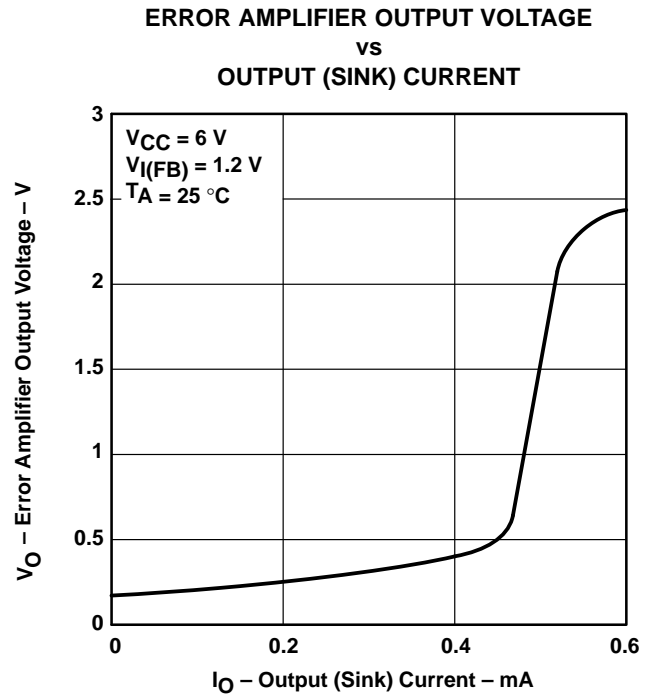
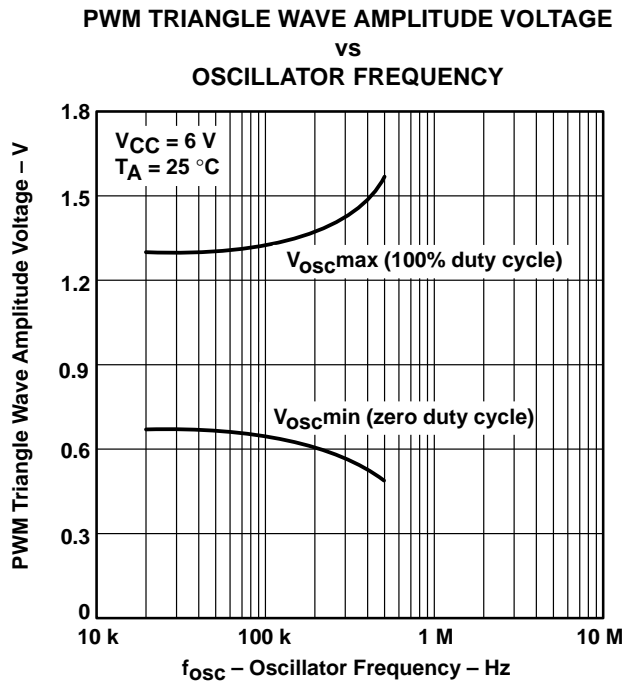
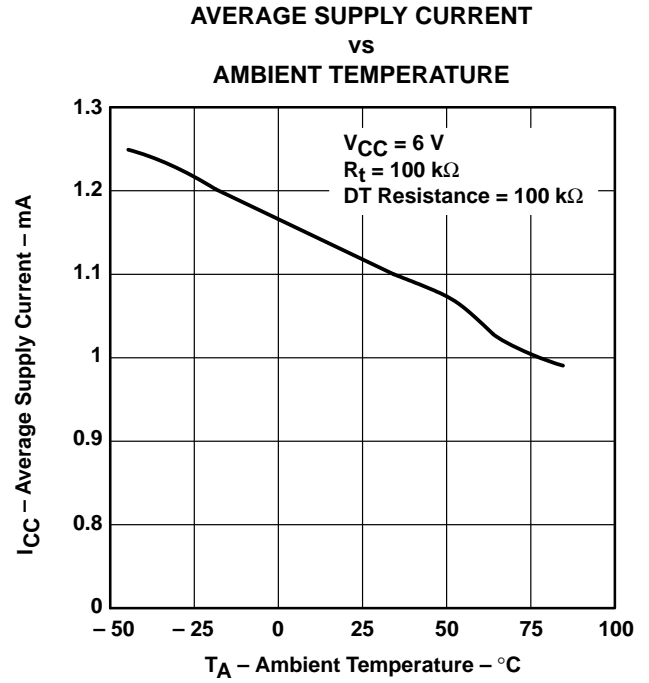
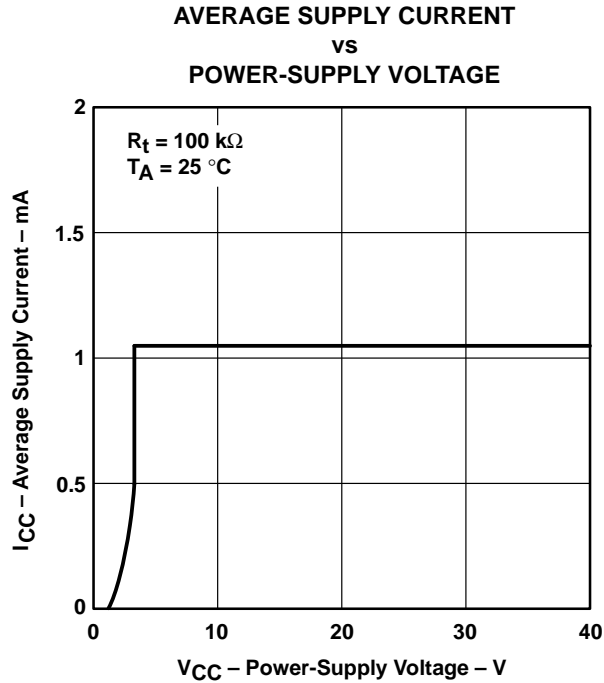


# TL5001, TL5001Y

## PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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### TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS

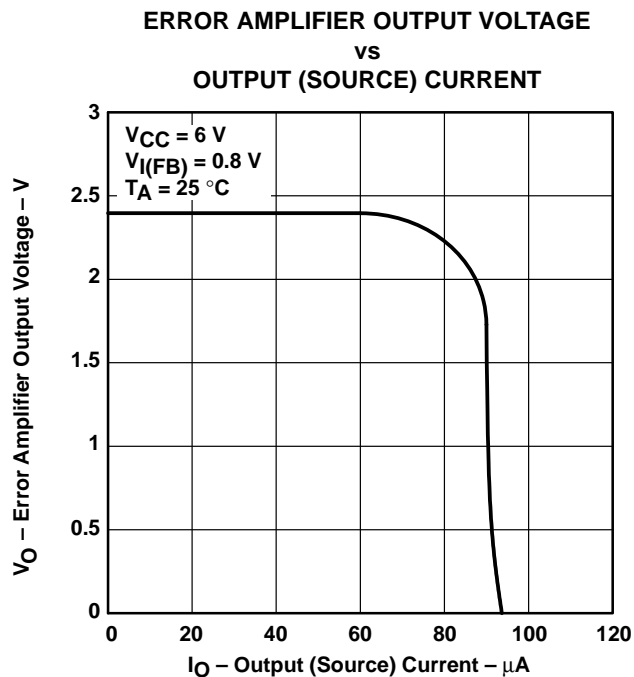


Figure 13

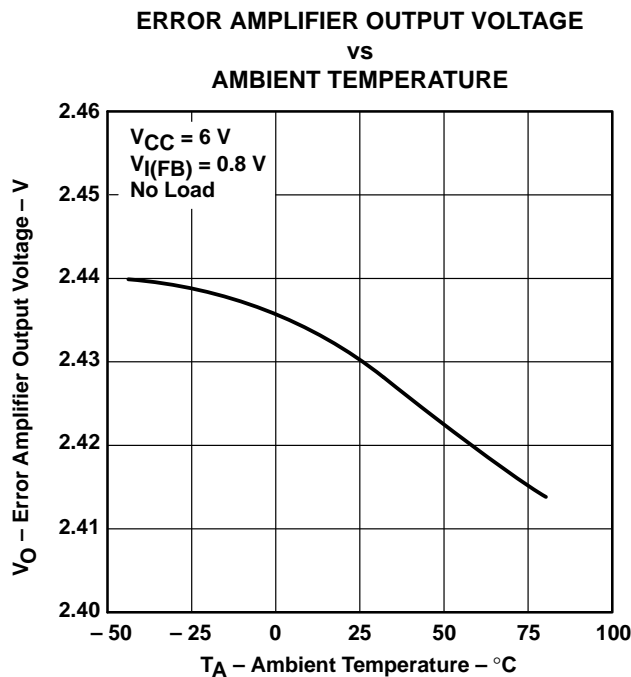


Figure 14

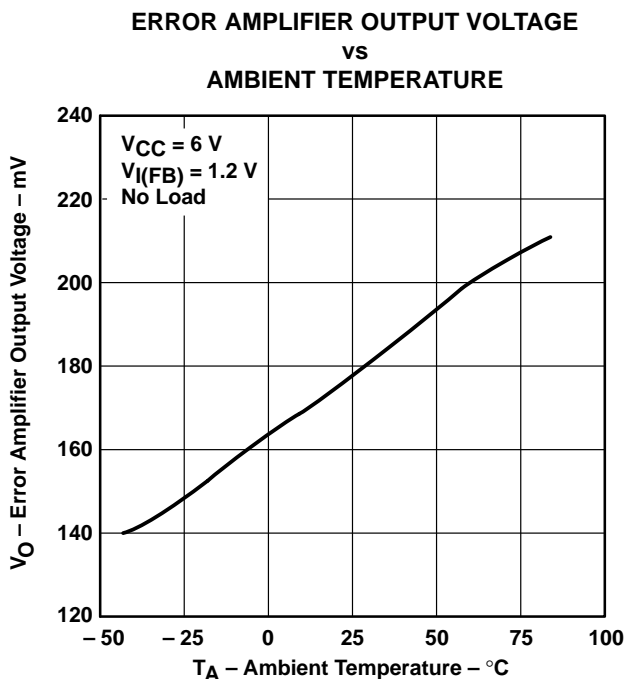


Figure 15

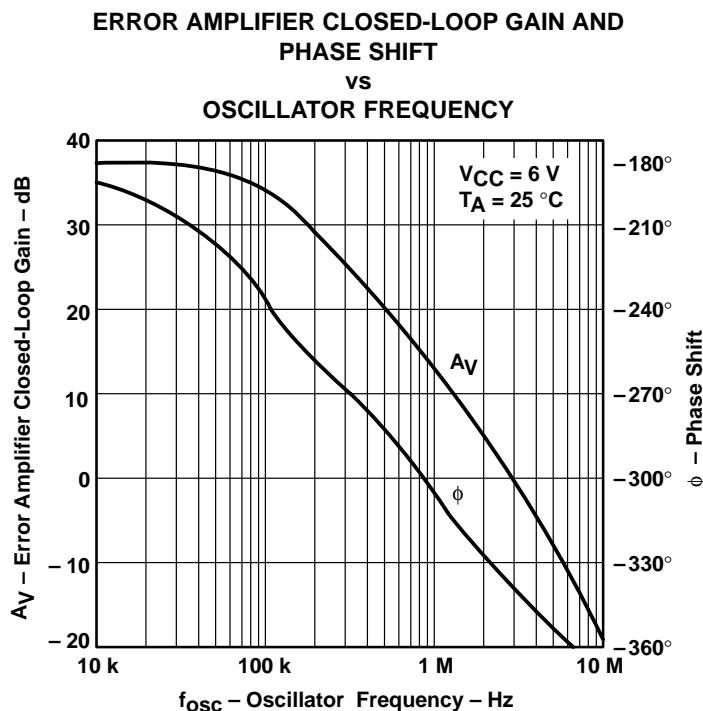


Figure 16

# TL5001, TL5001Y PULSE-WIDTH-MODULATION CONTROL CIRCUITS

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## TYPICAL CHARACTERISTICS

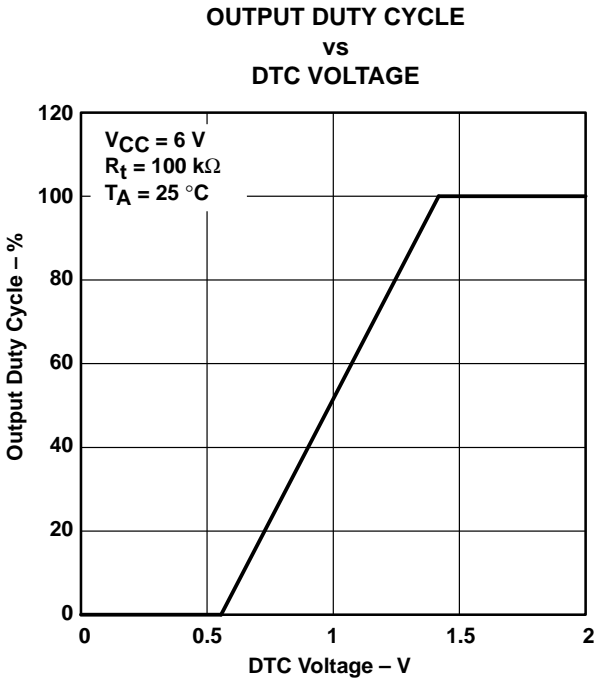


Figure 17

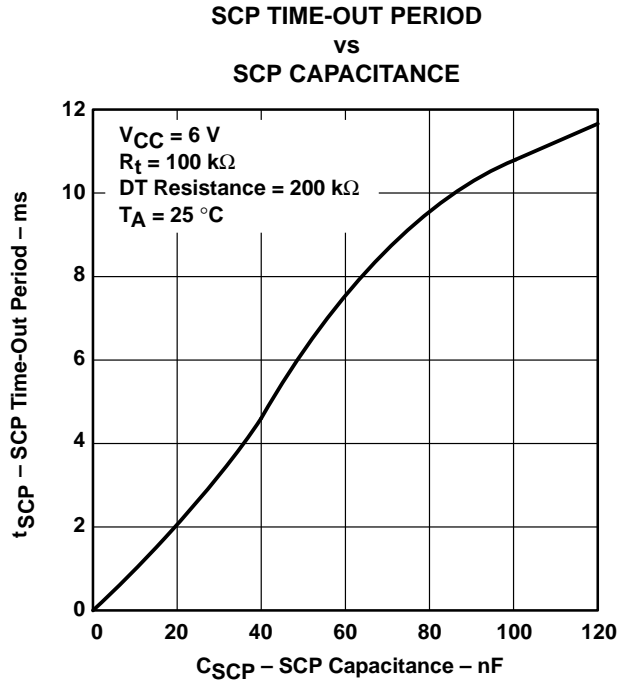


Figure 18

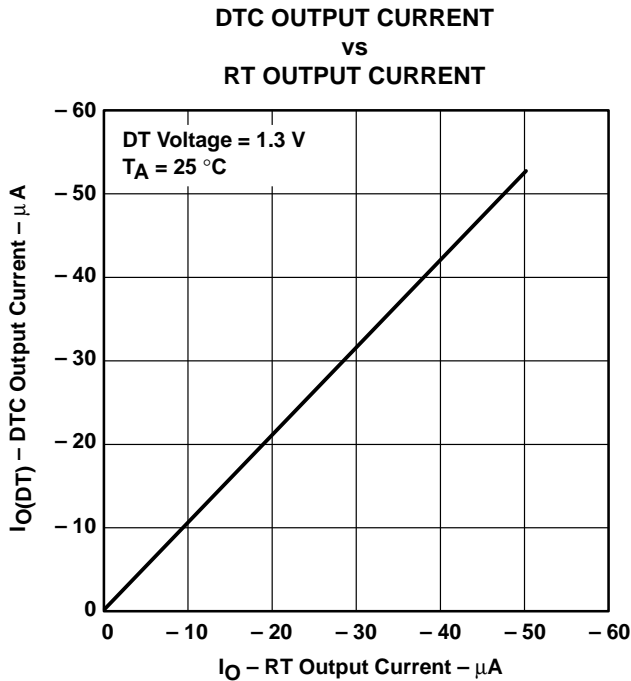


Figure 19

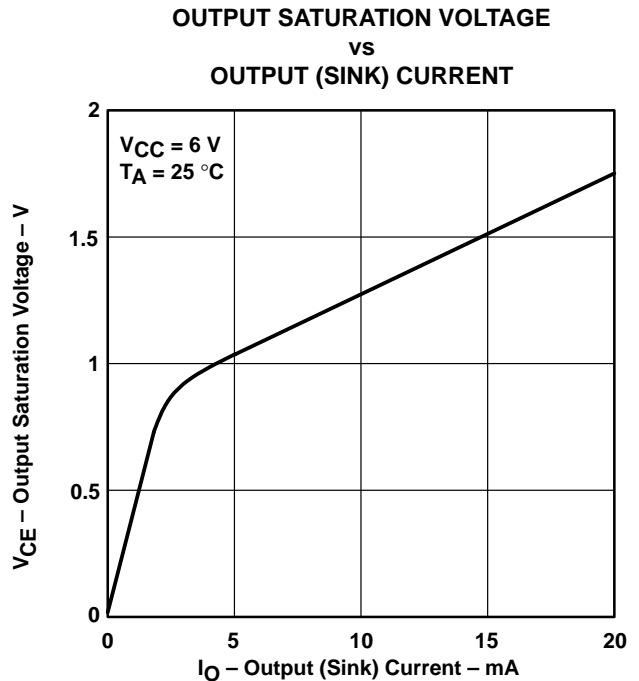
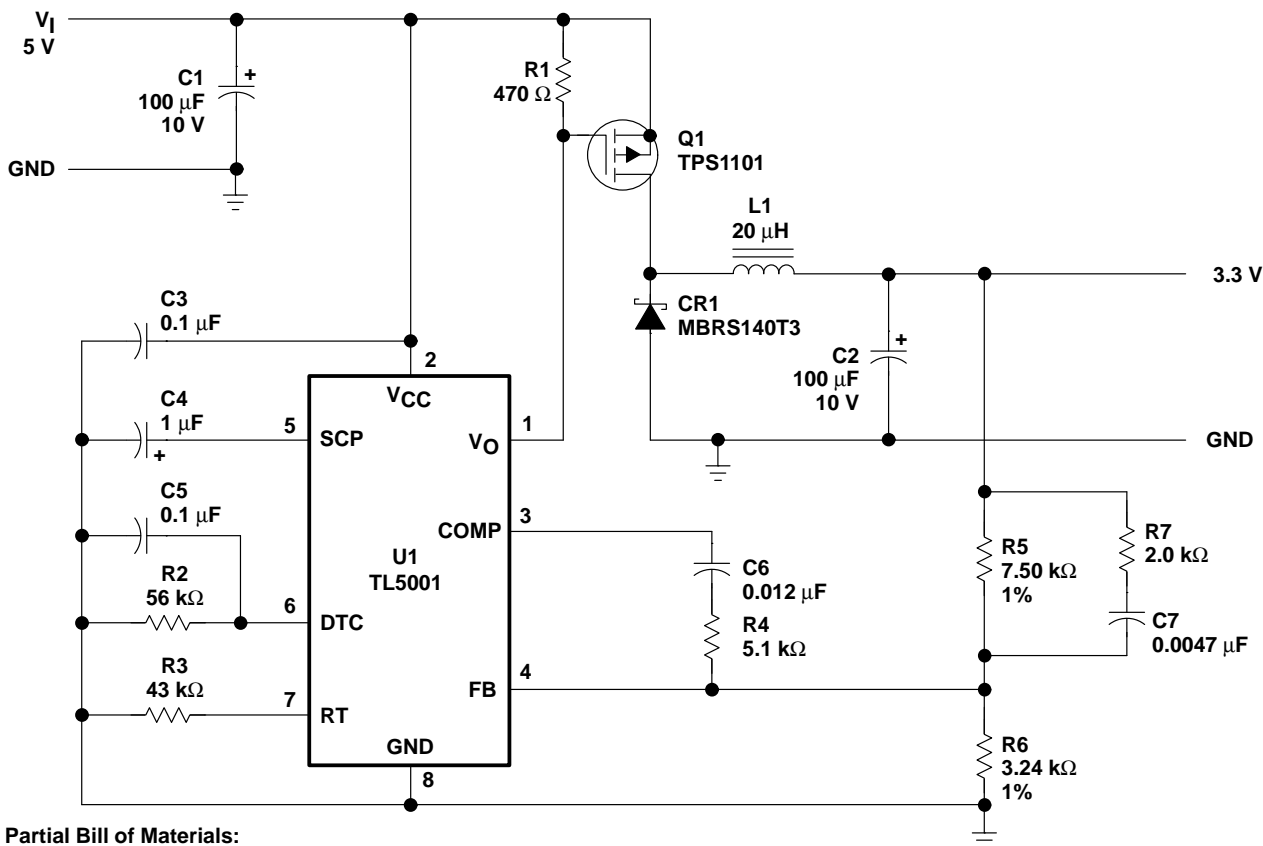


Figure 20



APPLICATION INFORMATION



Partial Bill of Materials:

U1	TL5001	Texas Instruments
Q1	TPS1101	Texas Instruments
L1	CTX20-1 or 23 turns of #28 wire on Micrometals No. T50-26B core	Coiltronics
C1	TPSD107M010R0100	AVX
C2	TPSD107M010R0100	AVX
CR1	MBRS140T3	Motorola

- NOTES: A. Frequency = 200 kHz  
 B. Duty cycle = 90% max  
 C. Soft-start time constant (TC) = 5.6 ms  
 D. SCP TC = 70 msA

Figure 21. Step-Down Converter



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